Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/676,654	TAKINAMI ET AL.
Examiner	Art Unit
Joseph Chang	2817

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Class	Subclass	Date	Examiner
331	117R,36C 177v, 179 117FE	6/8/2005	JC
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

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	DATE	EXMR
EAST (attached)	6/8/2005	JC
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